

This Page Is Inserted by IFW Operations  
and is not a part of the Official Record

## **BEST AVAILABLE IMAGES**

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

**IMAGES ARE BEST AVAILABLE COPY.**

**As rescanning documents *will not* correct images,  
please do not report the images to the  
Image Problem Mailbox.**

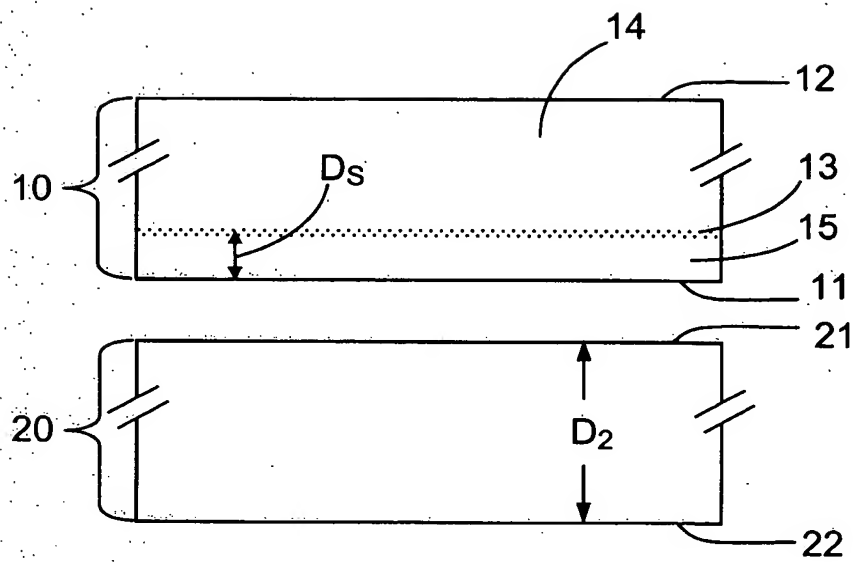


FIG. 1A

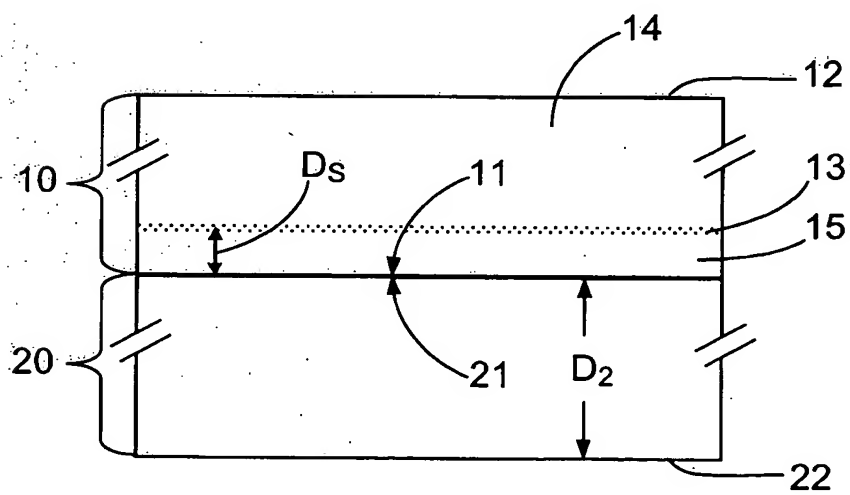


FIG. 1B

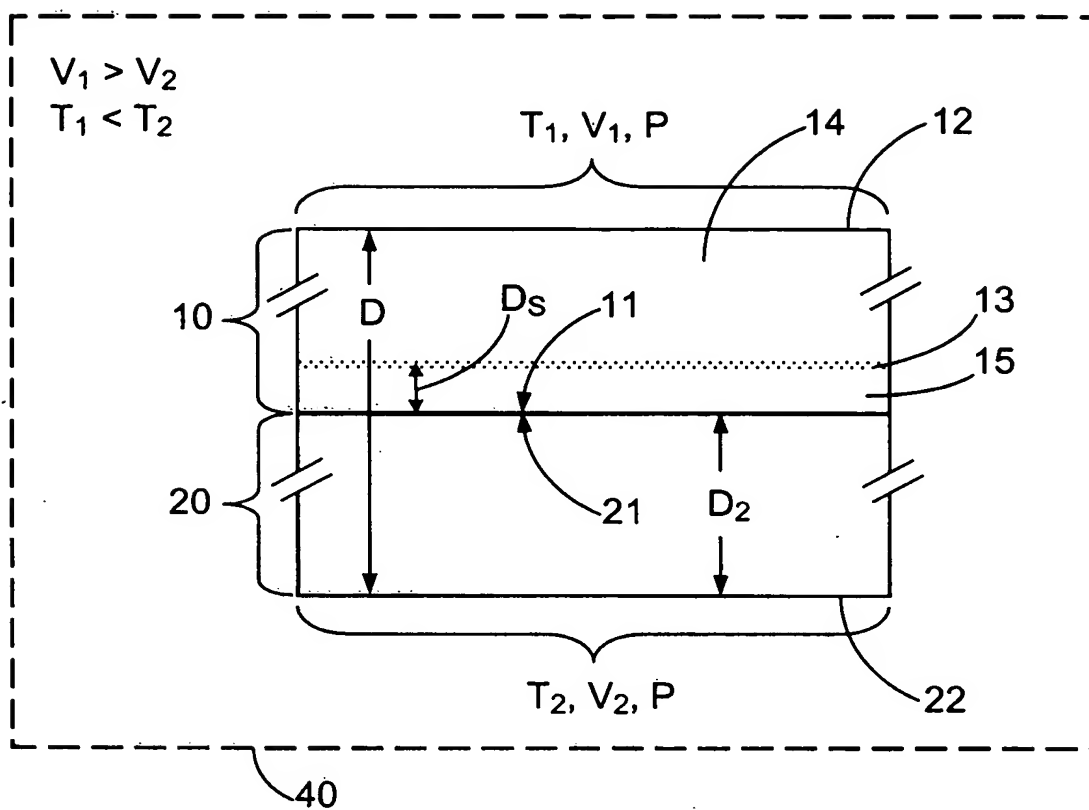


FIG. 1C

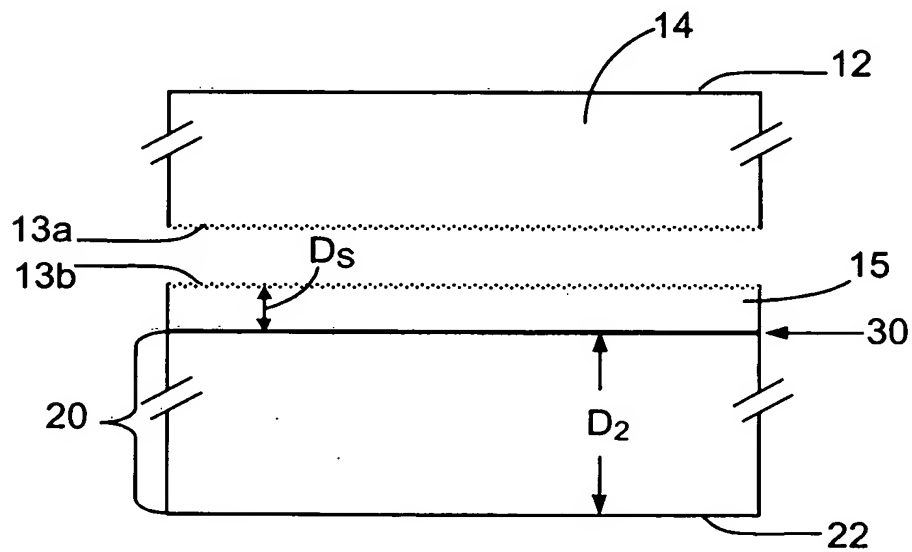


FIG. 1D

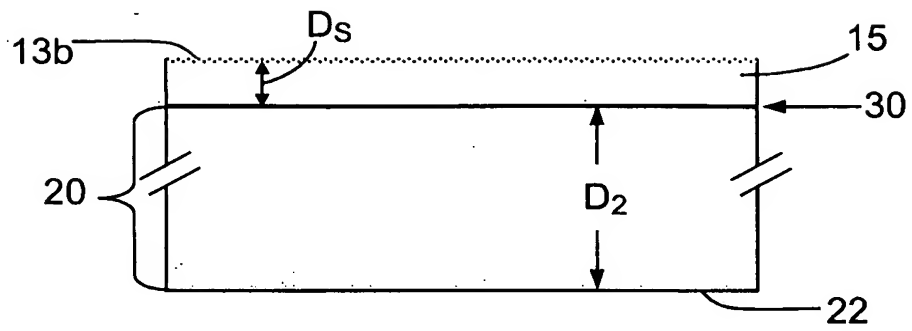


FIG. 2A

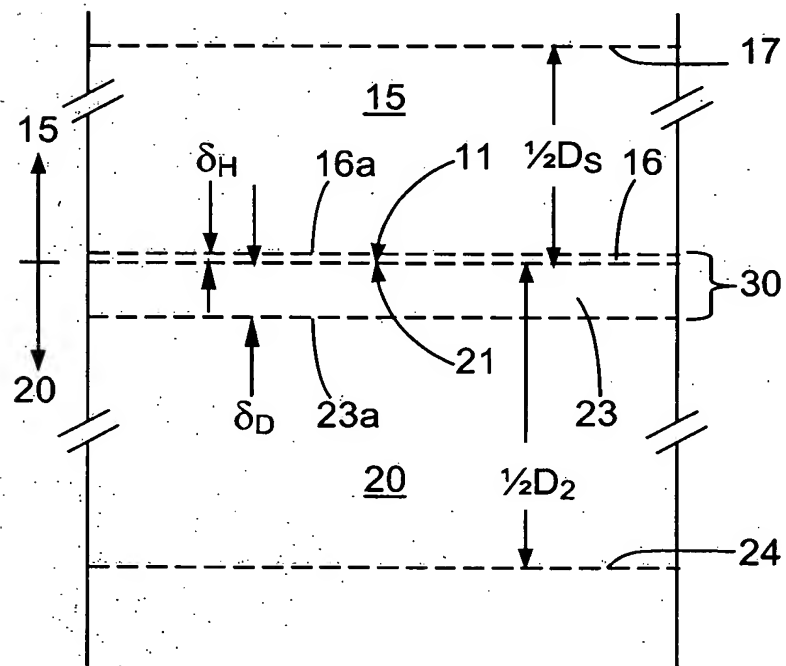


FIG. 2B

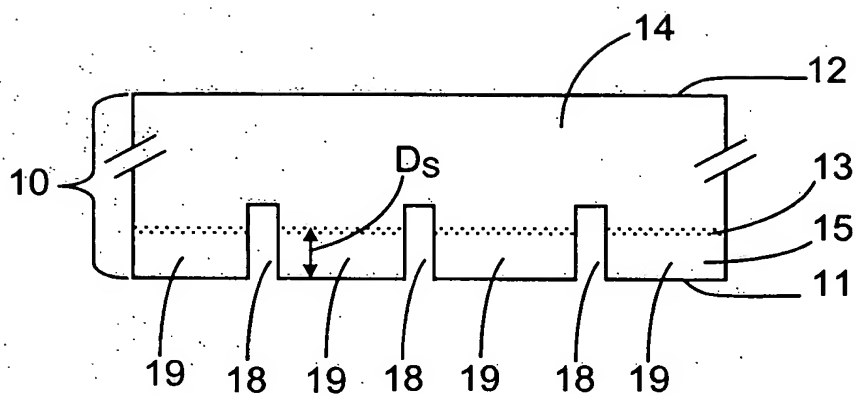


FIG. 3

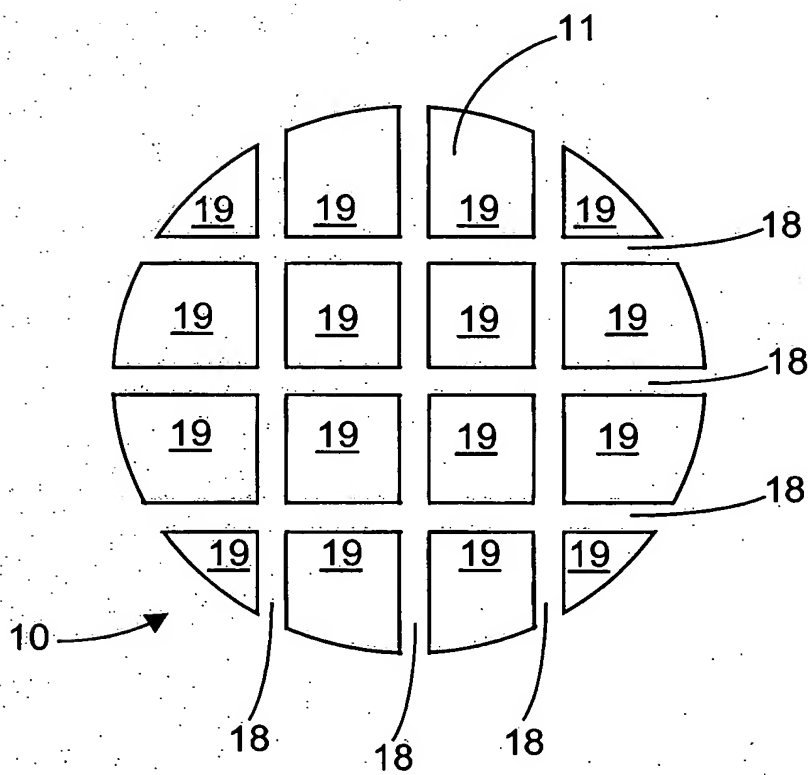


FIG. 4

5/16

ToF-SIMS DEPTH PROFILE OF Si/7070 (AS-BONDED)

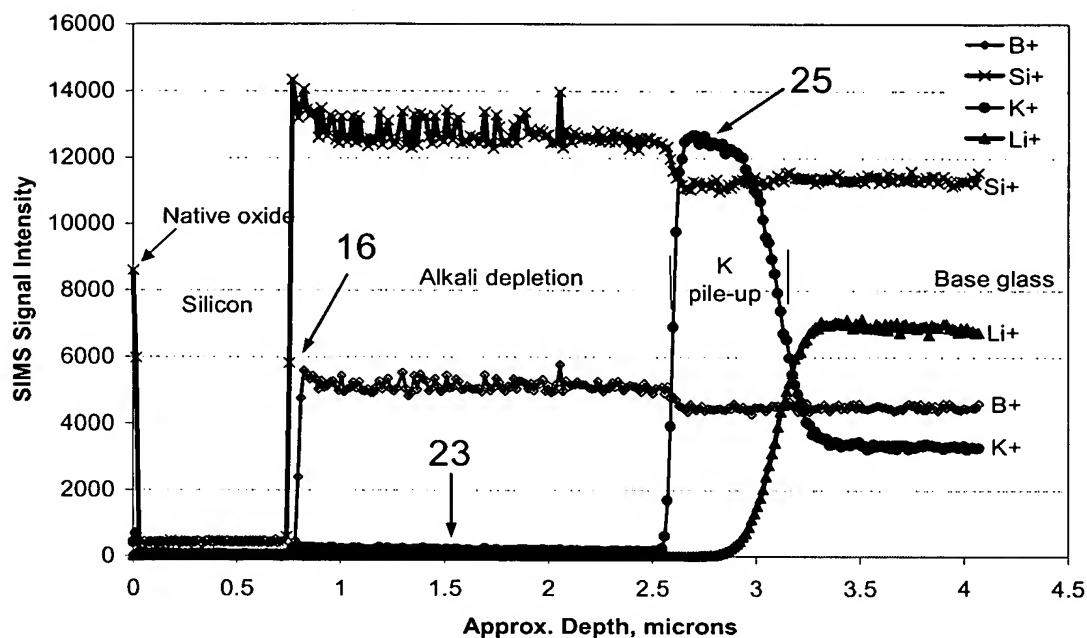


FIG. 5A

ToF-SIMS DEPTH PROFILE OF Si/7070 (AS BONDED)

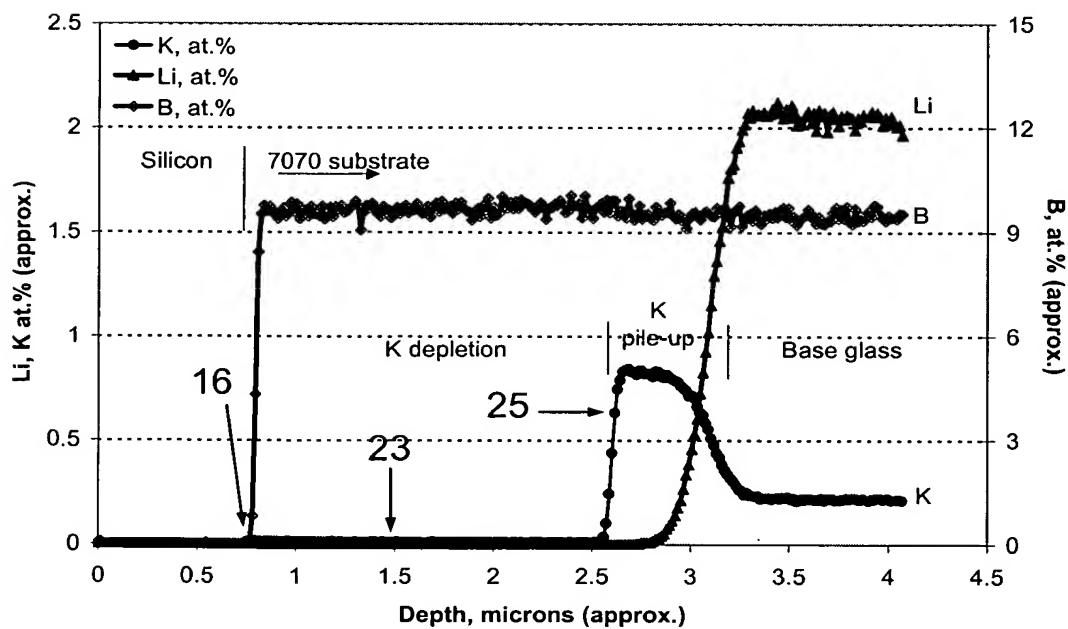


FIG. 5B

6/16

ToF-SIMS DEPTH PROFILE OF Si/7070 (RE-FIRED)

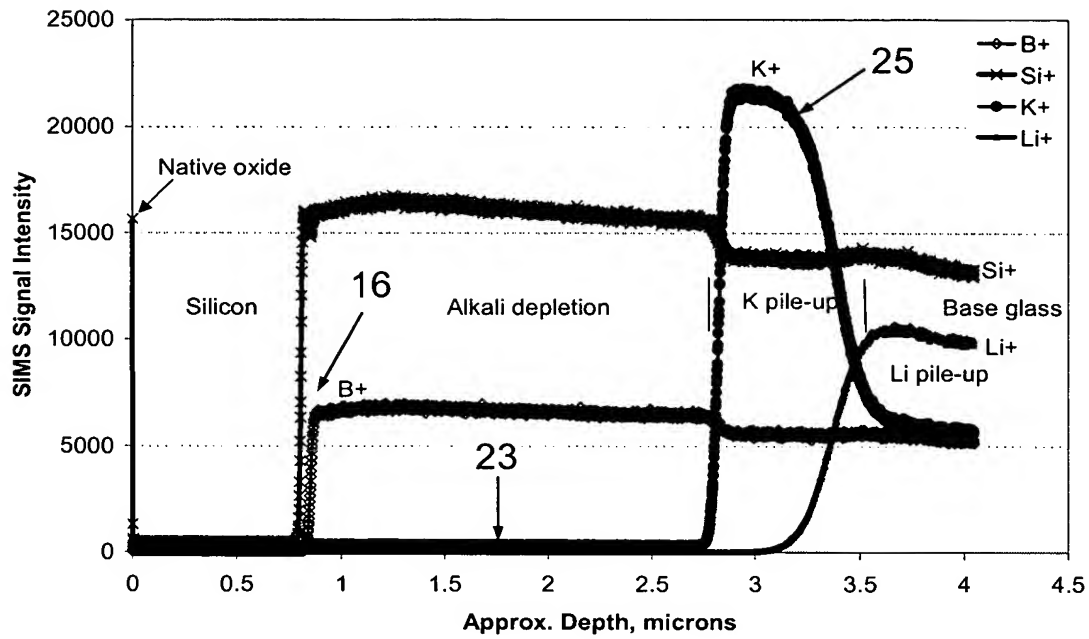


FIG. 6A

ToF-SIMS DEPTH PROFILE OF Si/7070 (RE-FIRED)

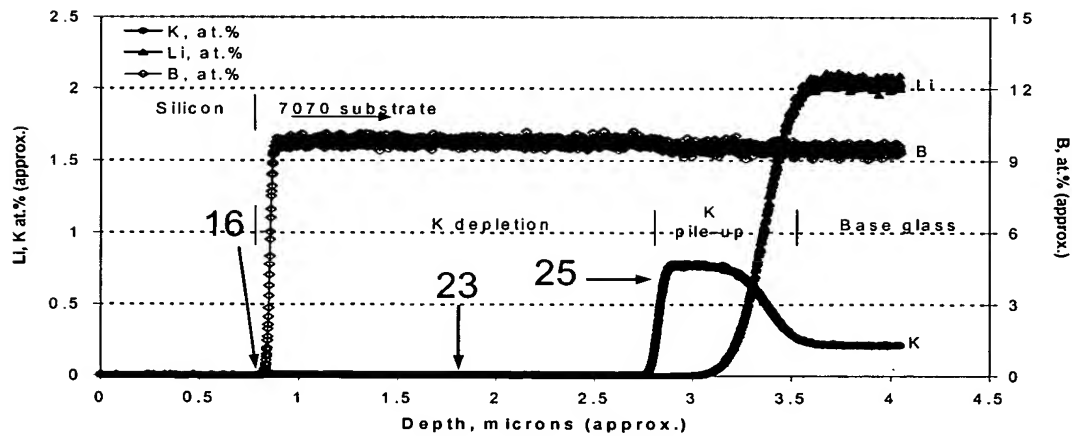
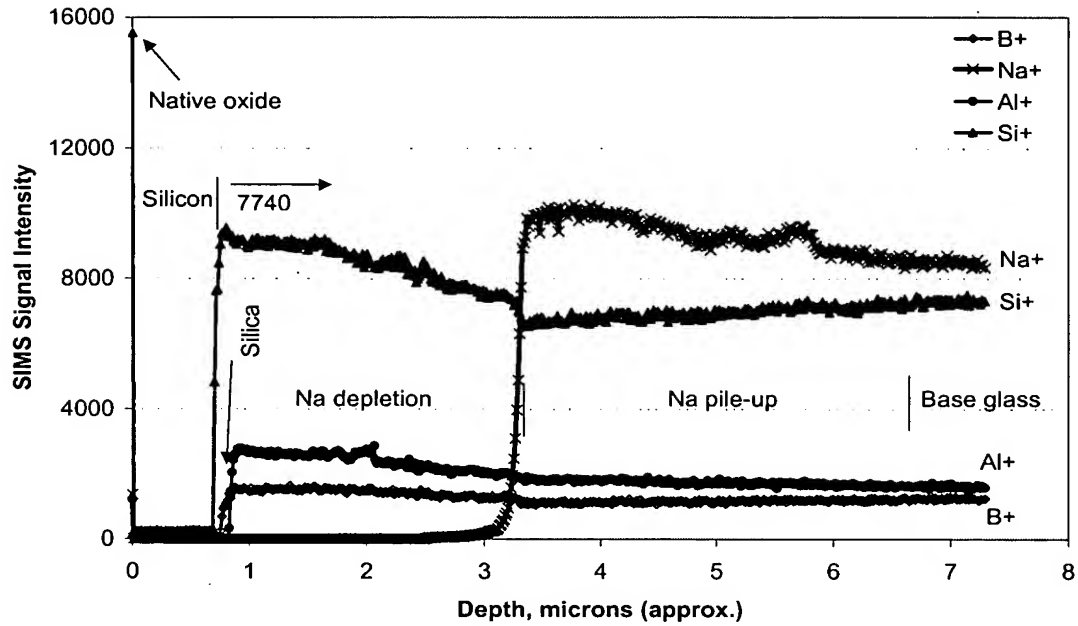


FIG. 6B

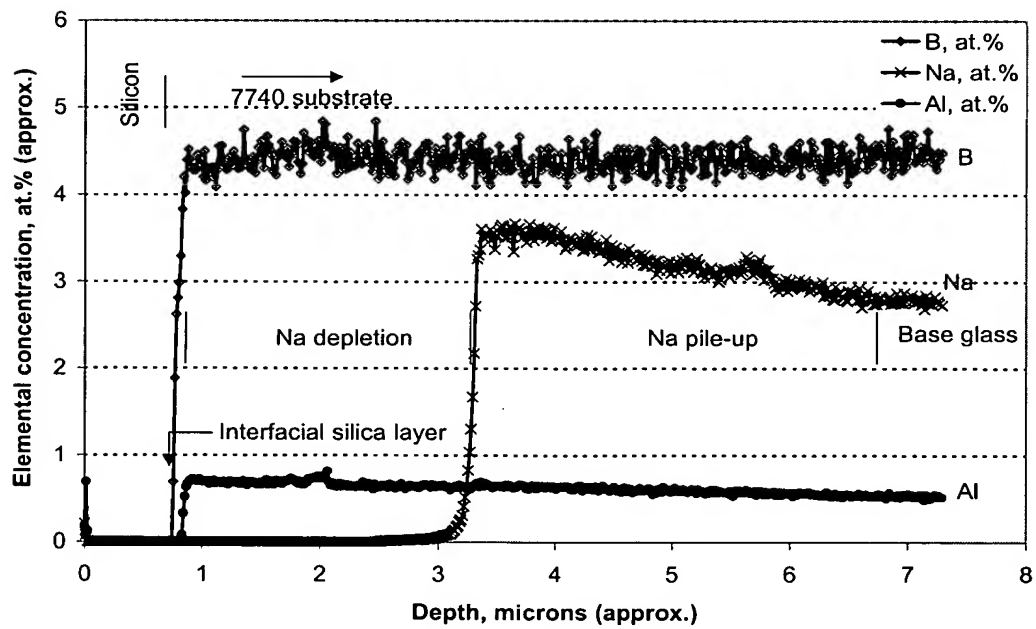
7/16

**ToF-SIMS DEPTH PROFILE OF Si/7740 (AS-BONDED)**



**FIG. 7A**

**ToF-SIMS DEPTH PROFILE OF Si/7740 (AS-BONDED)**



**FIG. 7B**



8/16

ToF-SIMS DEPTH PROFILE OF Si/7740 (RE-FIRED)

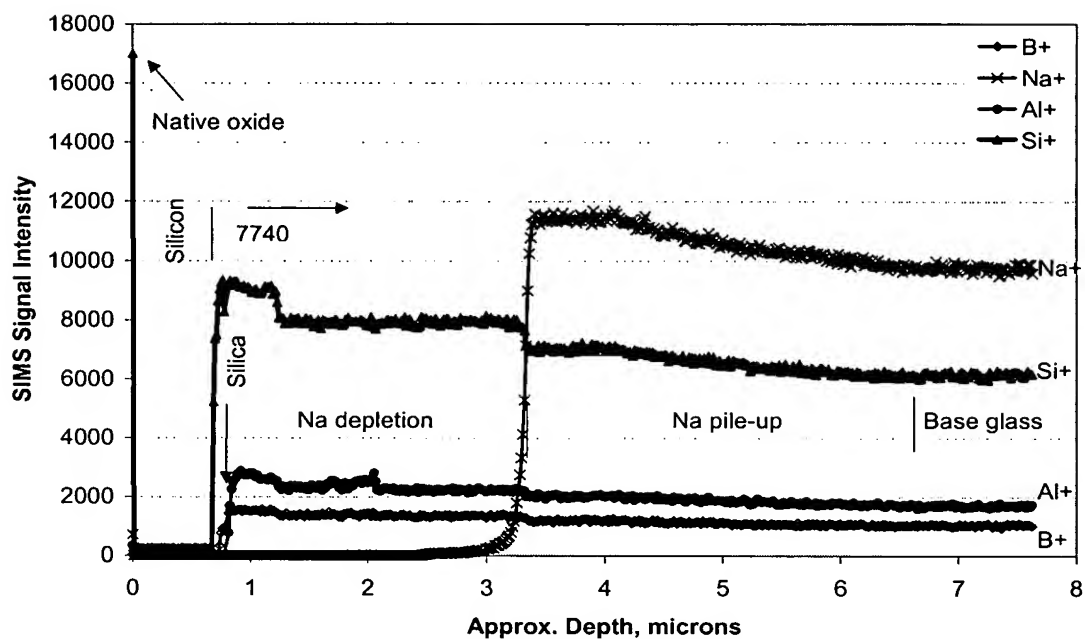


FIG. 8A

ToF-SIMS DEPTH PROFILE OF Si/7740 (RE-FIRED)

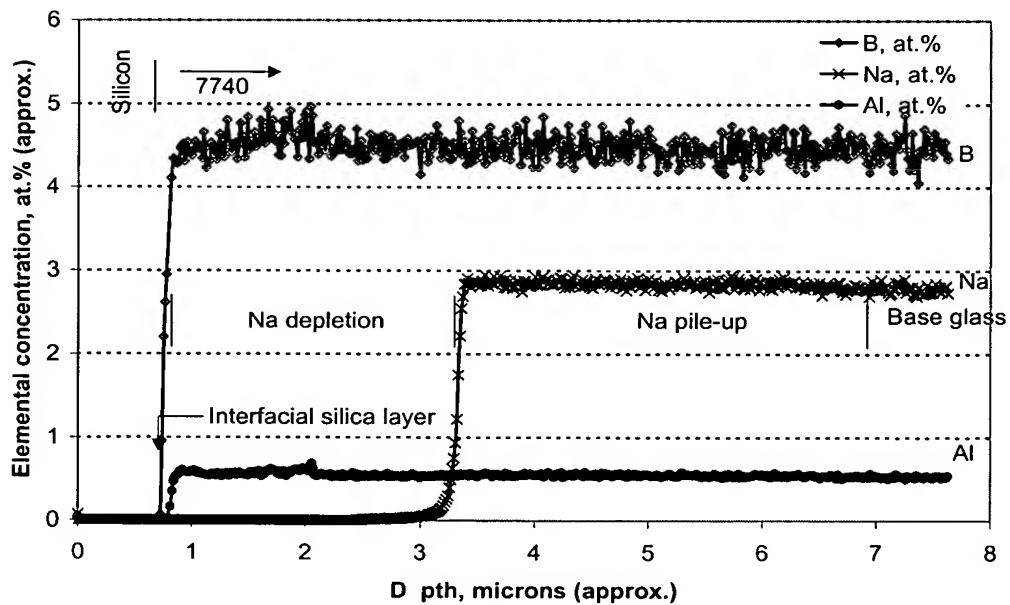


FIG. 8B

9/16

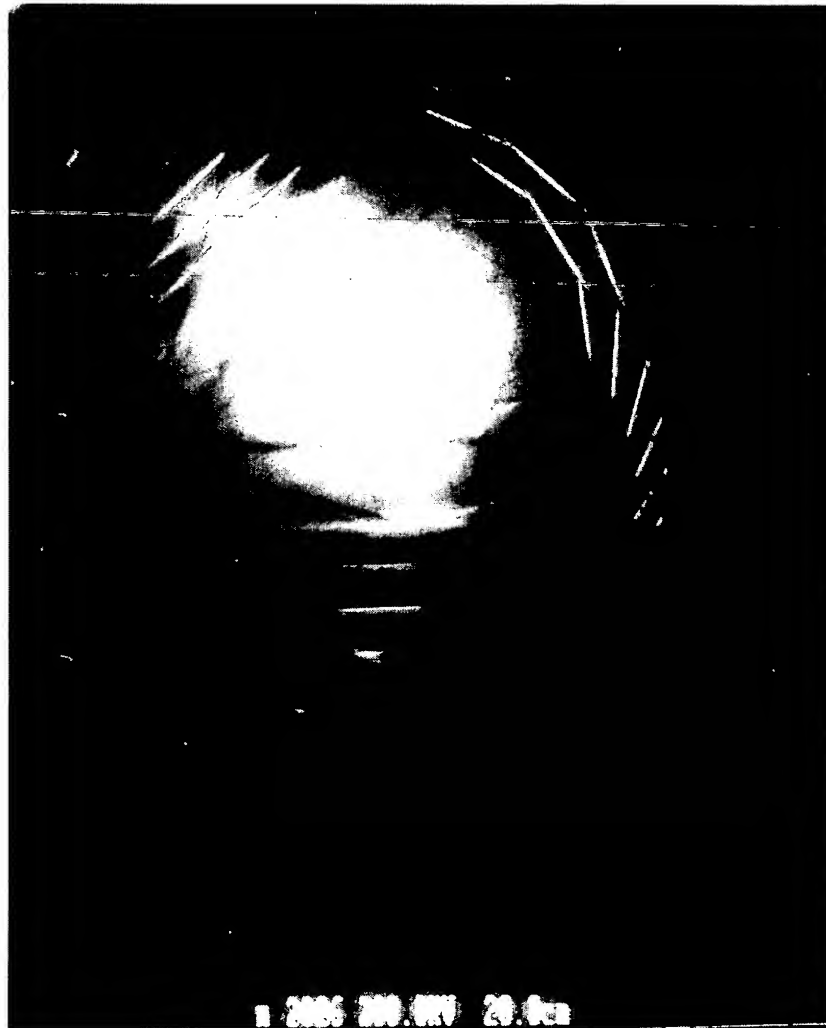


FIG. 9

# ToF-SIMS DEPTH PROFILE OF Si/1737

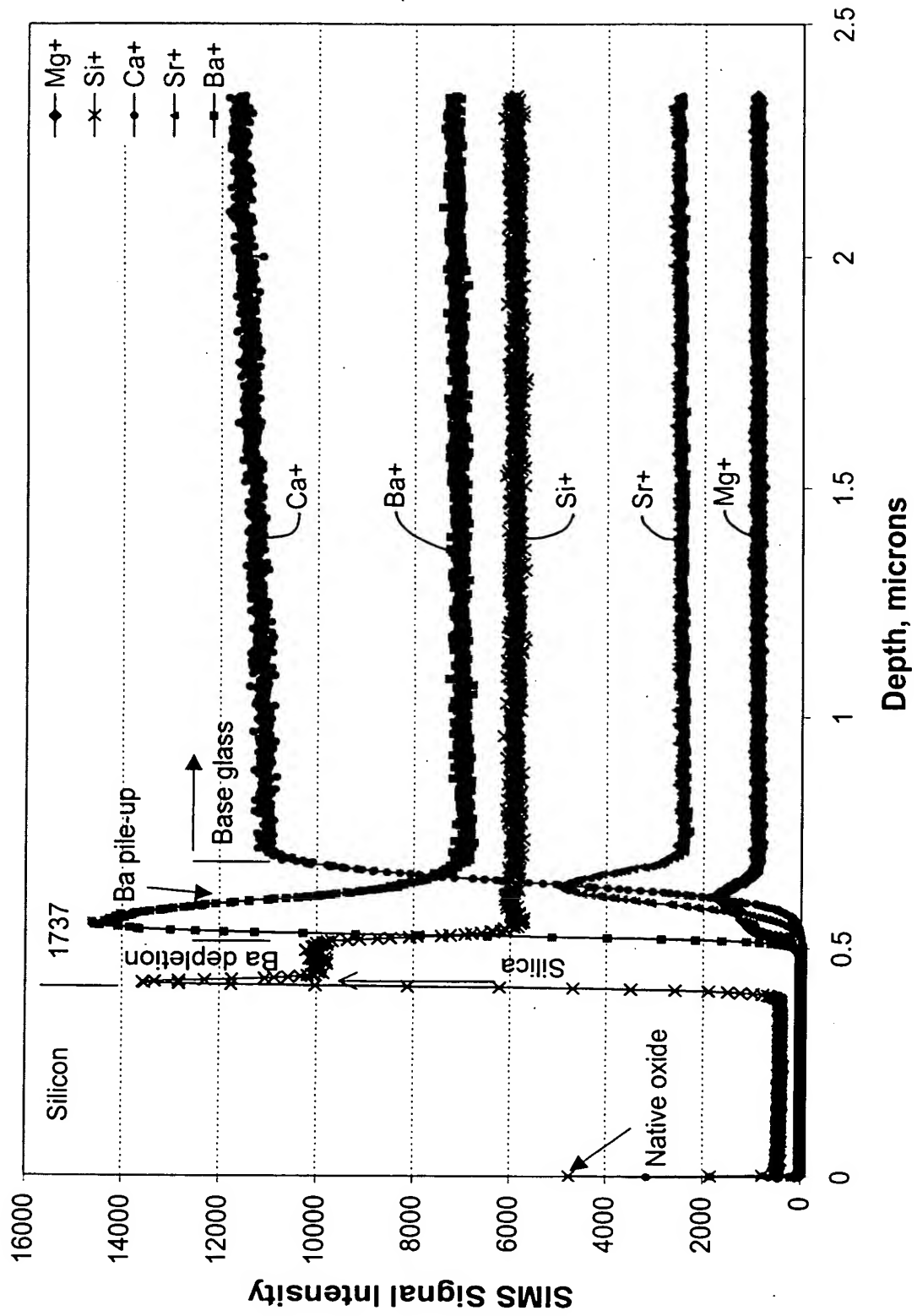
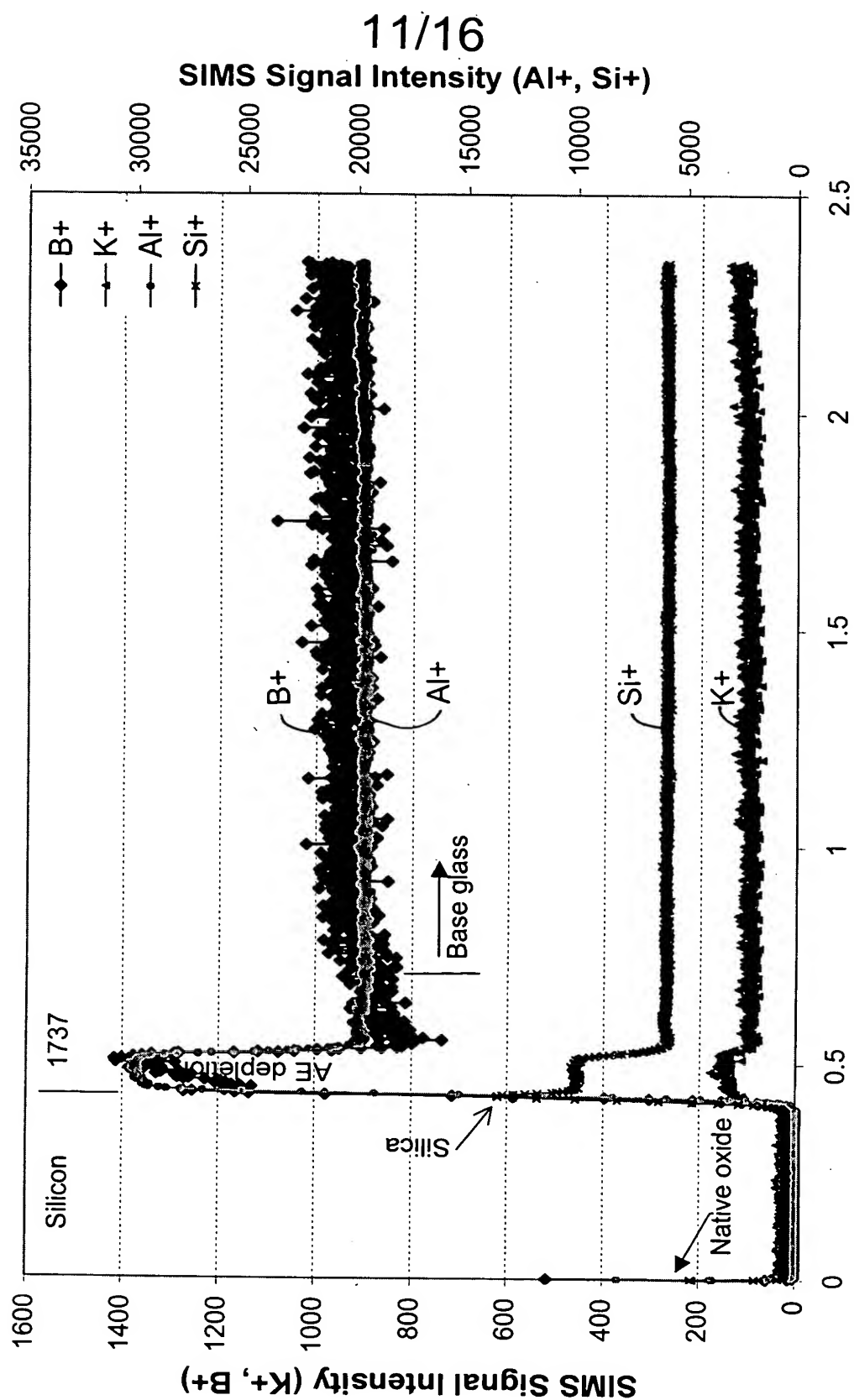


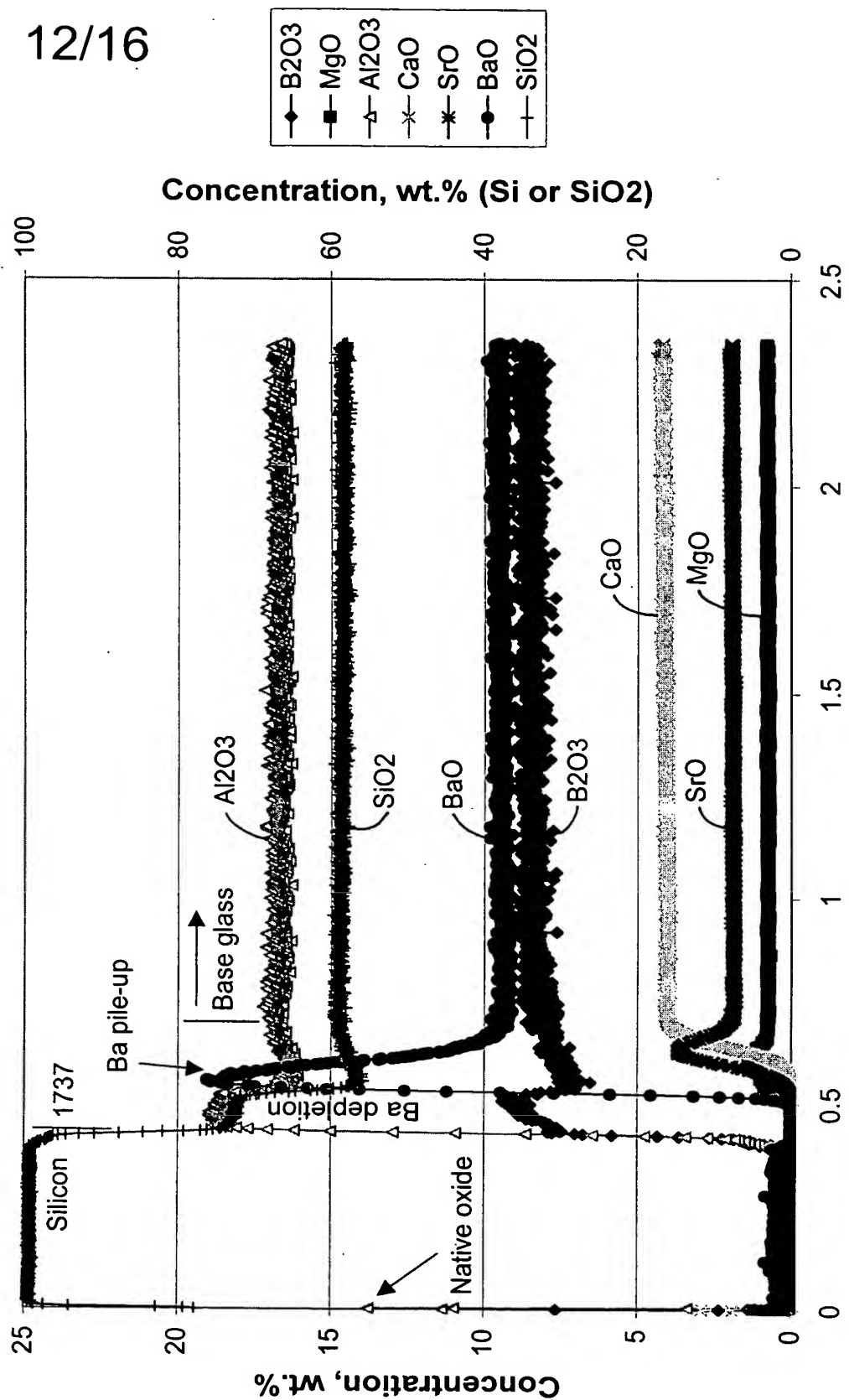
FIG. 10A

# ToF-SIMS DEPTH PROFILE OF Si/1737



# ToF-SIMS DEPTH PROFILE OF Si/1737

12/16



Depth, microns  
FIG. 10C

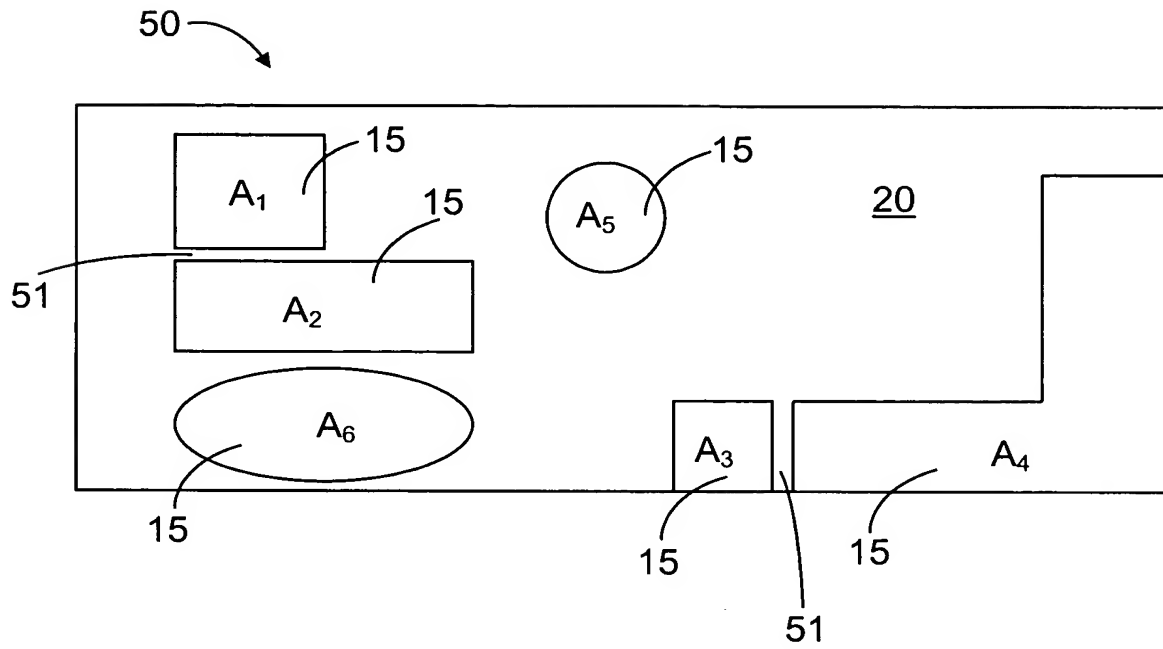


FIG. 11

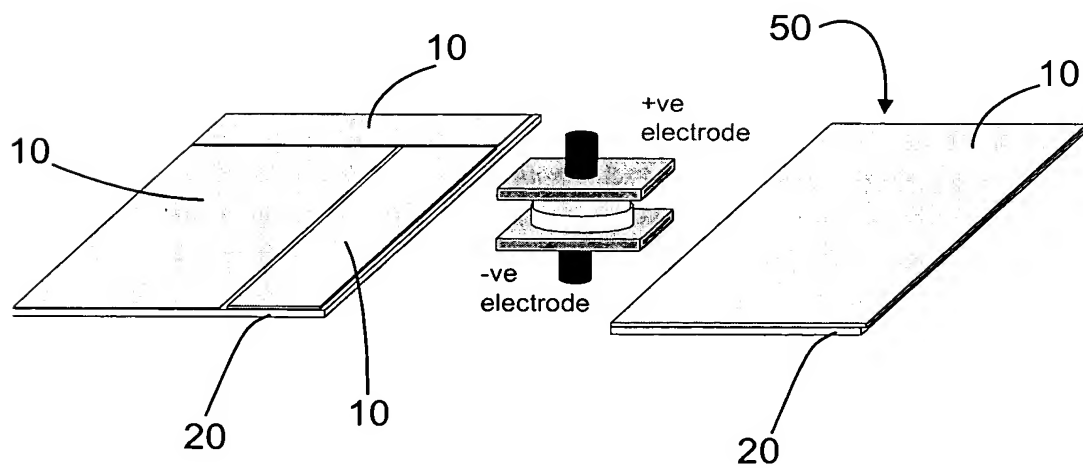


FIG. 12

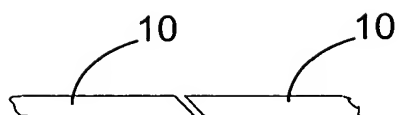


FIG. 13A

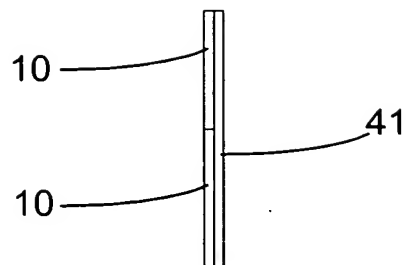


FIG. 13B

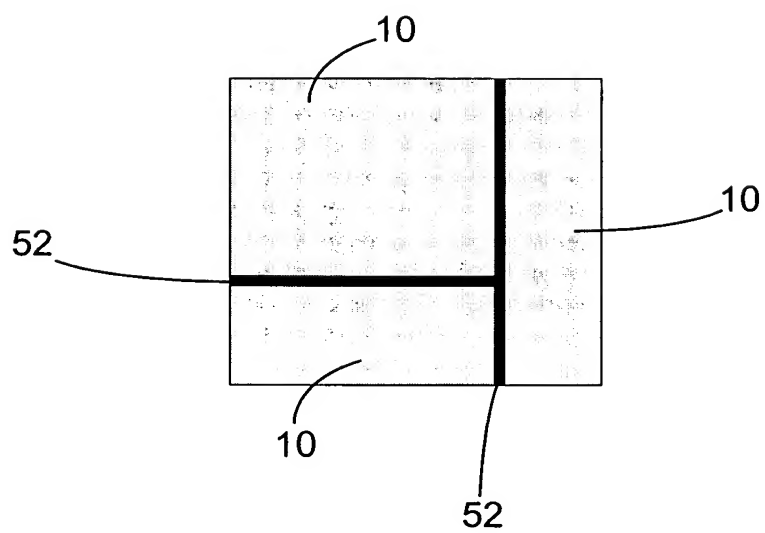


FIG. 14

PRIOR ART

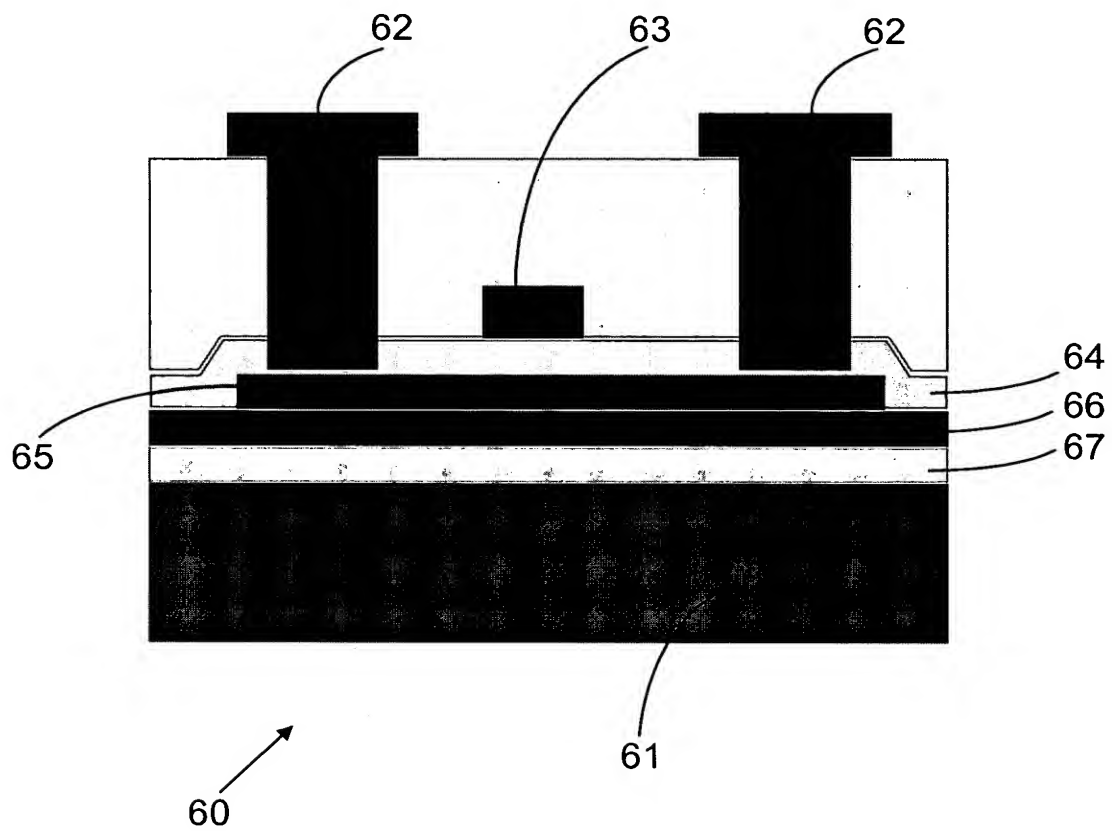


FIG. 15



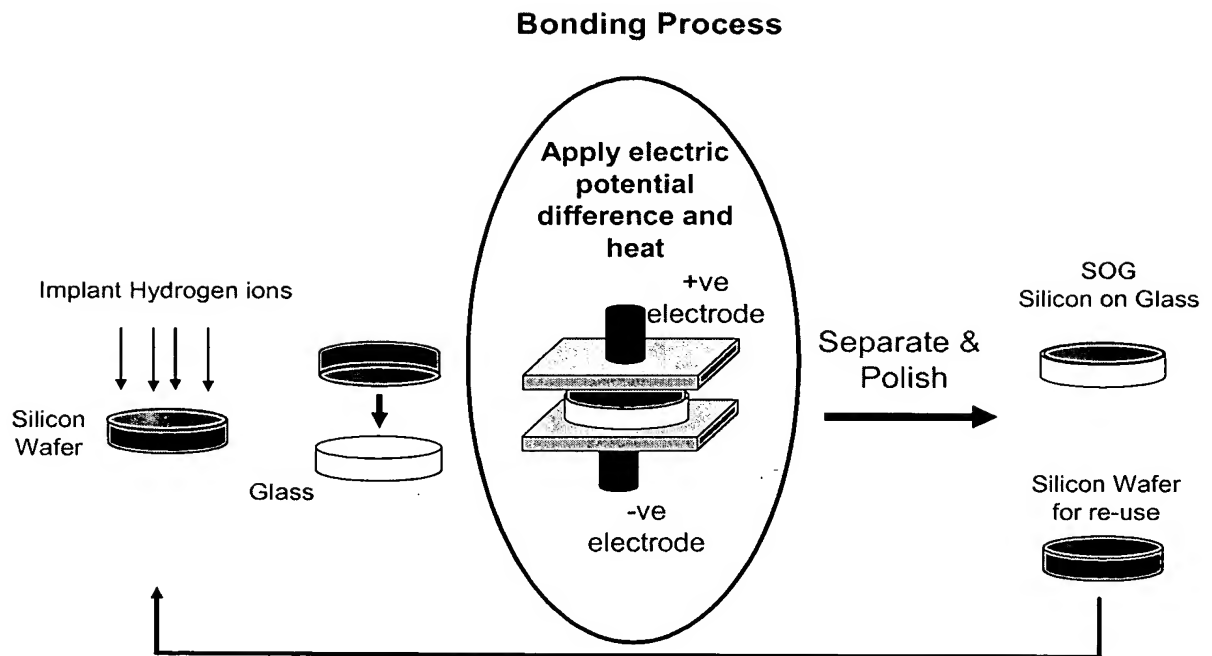


FIG. 16